Notice of References Cited

	Application/Control No. 09/683,546	Applicant(s)/Patent Under Reexamination HAYES, JERRY D.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,584,606	06-2003	Chiu et al.	716/10
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	P.F. Tehrani et al., Extraction of Transient Behavioral Model of Digital I/O Buffers from IBIS, Proceedings of Electronic Components and Technology Conference, pages 1009-1015, May 1996.
	V	T. Zak et al., An Experimental Procedure to Derive Reliable IBIS Models, Proceedings of the 3rd Electronics Packaging Technology Conference, pages 339-344, December 2000.
	W	Y. Wang et al., The Development of Analog SPICE Behavioral Model Based on IBIs Model, Proceedings of the Ninth Great Lakes Symposium on VLSI, pages 101-104, March 1999.
	X	J. D. Hayes et al., Behavioral Modeling for Timing, Noise, and Signal Integrity Analysis, IEEE Conference on Custom Integrate Circuits, pages 353-356, May 2001.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

		Notice of References Cited	Application/Control No. 09/683,546	Applicant(s)/Patent Under Reexamination HAYES, JERRY D.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	J.D. Hayes et al., Using Voltage and Temperature Adders To Account for Variations in Operating Conditions During Digital Timing Simulation, Tenth Annual IEEE International ASIC Conference and Exhibit, pages 348-351, September 1997.
	V	B. Ackalloor et al., An Overview of Library Characterization in Secmi-Custom Design, IEEE 1998 Custom Integrated Circuits Conference, pages 305-312, May 1998.
	W	I.S. Stievano et al., Behavioral Modeling of Digital IC Input and Output Ports, Electrical Performance of Electronic Packaging, pages 331-334, October 2001.
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.